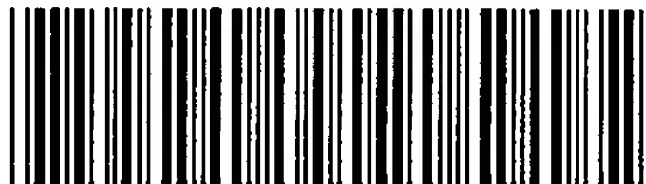


Search Notes



Application/Control No.

10/624,506

Examiner

Edward Wojciechowicz

Applicant(s)/Patent under
Reexamination

BYEON ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	390	10-15-05	EH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
See search history	10-15-05	EH